

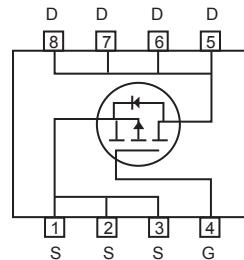
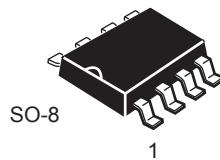
## P-Channel Enhancement Mode Field Effect Transistor

PRELIMINARY

## FEATURES

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- -60V, -3.7A,  $R_{DS(ON)} = 125m\Omega$  @ $V_{GS} = -10V$ .  
 $R_{DS(ON)} = 165m\Omega$  @ $V_{GS} = -4.5V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handing capability.
- Lead free product is acquired.
- Surface mount Package.

ABSOLUTE MAXIMUM RATINGS  $T_A = 25^\circ C$  unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	$V_{DS}$	-60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	-3.7	A
Drain Current-Pulsed <sup>a</sup>	$I_{DM}$	-14.8	A
Maximum Power Dissipation	$P_D$	2.5	W
Operating and Store Temperature Range	$T_J, T_{Stg}$	-55 to 150	$^\circ C$

## Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Ambient <sup>b</sup>	$R_{\theta JA}$	50	$^\circ C/W$

**CEM9407A****P-Channel Electrical Characteristics**  $T_A = 25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-60			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = -48\text{V}, V_{\text{GS}} = 0\text{V}$			-1	$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
<b>On Characteristics<sup>c</sup></b>						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = -250\mu\text{A}$	-1		-3	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_D = -3.7\text{A}$		100	125	$\text{m}\Omega$
Forward Transconductance	$g_{\text{FS}}$	$V_{\text{DS}} = -5\text{V}, I_D = -3.7\text{A}$		130	165	$\text{m}\Omega$
<b>Dynamic Characteristics<sup>d</sup></b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		615		pF
Output Capacitance	$C_{\text{oss}}$			140		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			45		pF
<b>Switching Characteristics<sup>d</sup></b>						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -30\text{V}, I_D = -1\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 6\Omega$		11	22	ns
Turn-On Rise Time	$t_r$			4.5	9	ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			50	100	ns
Turn-Off Fall Time	$t_f$			15	30	ns
Total Gate Charge	$Q_g$	$V_{\text{DS}} = -30\text{V}, I_D = -3.7\text{A}, V_{\text{GS}} = -10\text{V}$		17	22	nC
Gate-Source Charge	$Q_{\text{gs}}$			2		nC
Gate-Drain Charge	$Q_{\text{gd}}$			4		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current <sup>b</sup>	$I_S$				-1.3	A
Drain-Source Diode Forward Voltage <sup>c</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_S = -1.3\text{A}$			-1.2	V

## Notes :

- a.Repetitive Rating : Pulse width limited by maximum junction temperature.
- b.Surface Mounted on FR4 Board, t ≤ 10 sec.
- c.Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
- d.Guaranteed by design, not subject to production testing.



# CEM9407A

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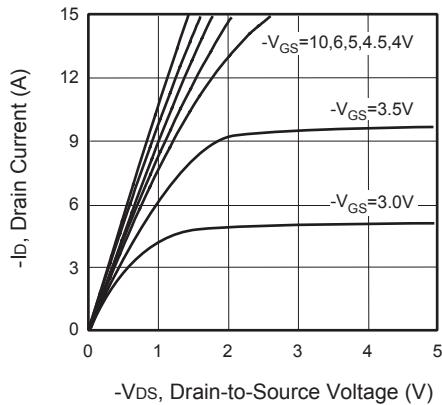


Figure 1. Output Characteristics

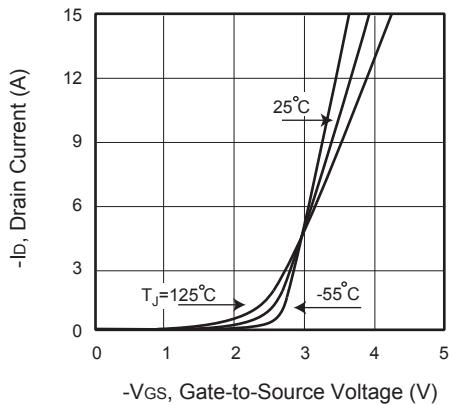


Figure 2. Transfer Characteristics

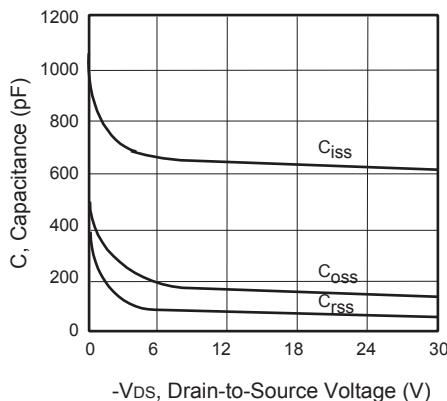


Figure 3. Capacitance

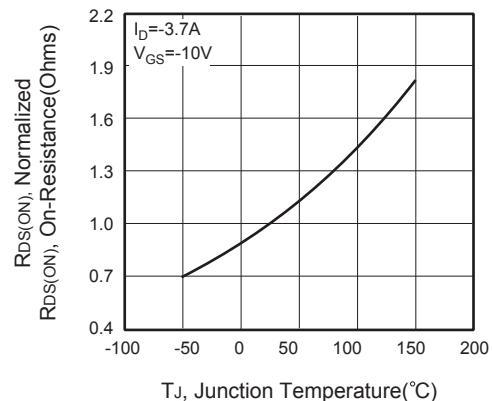


Figure 4. On-Resistance Variation with Temperature

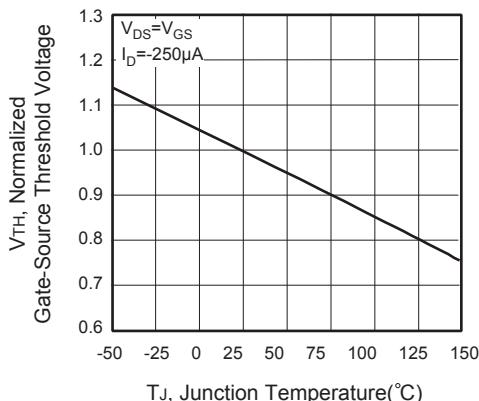


Figure 5. Gate Threshold Variation with Temperature

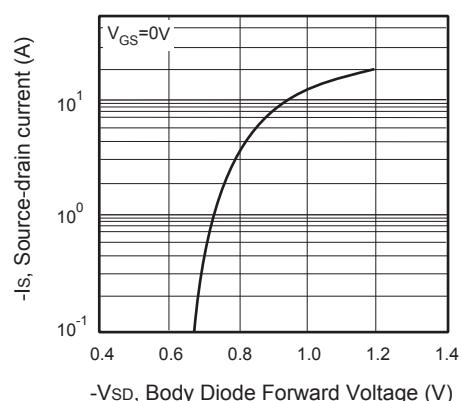


Figure 6. Body Diode Forward Voltage Variation with Source Current

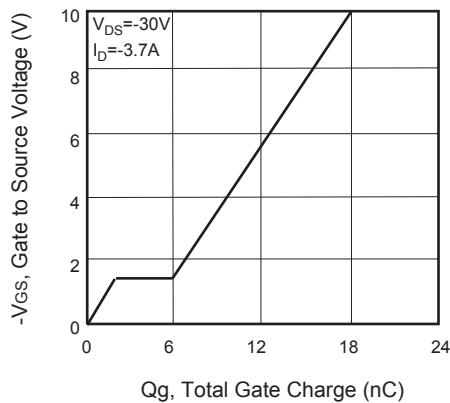


Figure 7. Gate Charge

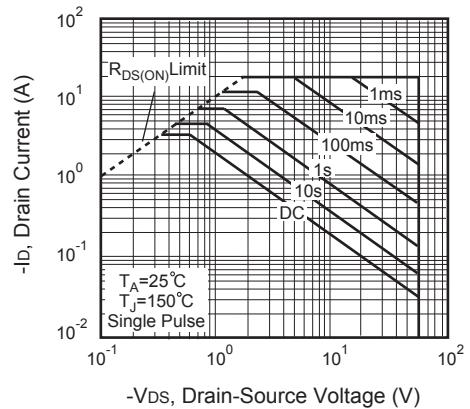


Figure 8. Maximum Safe Operating Area

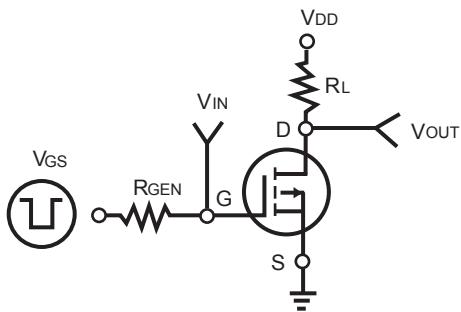


Figure 9. Switching Test Circuit

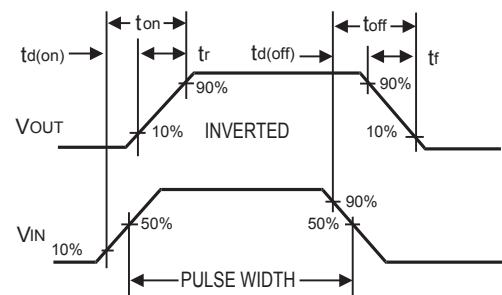


Figure 10. Switching Waveforms

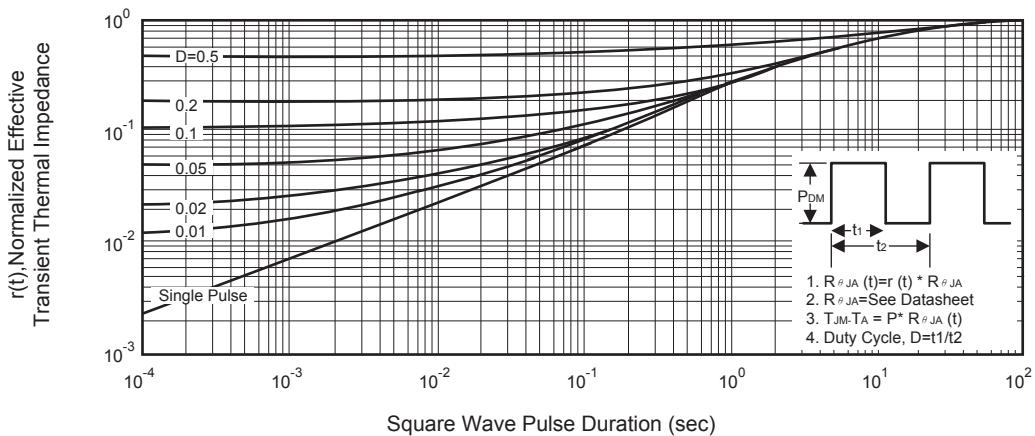


Figure 11. Normalized Thermal Transient Impedance Curve